

## **HZB KESTCELLS seminar #2**

## The CISSY surface and interface analysis system at BESSY II

Friday March 27th at 10:00 in room 13.10-428, Magnusstraße 2, 12489 Berlin, Campus Adlershof

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In 2002, a new instrument for surface and interface analysis was set up at BESSY II. The CISSY system (the name was derived from CIS and SYnchrotron) was designed to be both a laboratory surface analysis system and a synchrotron end station, equipped with an electron analyser, an x-ray spectrometer and ion, electron, X-ray and UV-sources. Furthermore, CISSY comprises a directly connected sputter deposition chamber for the preparation of a wide range of materials, especially oxides, oxo-sulfides and sulfides and a nitrogen-flushed glove box to provide an oxygen-free environment for wet-chemical preparation. The primary goal of CISSY is the preparation and characterization of surfaces and interfaces in compound semiconductor thin film solar cells like kesterite or chalcopyrite devices and their components. Selected results from research conducted with CISSY will be presented and the concept of the CISSY system will be discussed especially in comparison to other end stations at BESSY II.